



JOURNAL OF EMERGING TECHNOLOGIES AND INNOVATIVE RESEARCH (JETIR)

An International Scholarly Open Access, Peer-reviewed, Refereed Journal

Ref No : JETIR / Vol 10 / Issue 2 / 292

Confirmation Letter

To,

Arman Ahmad

Published in : Volume 10 | Issue 2 | 2023-02-21



Subject: Publication of paper at International Journal of Emerging Technologies and Innovative Research .

Dear Author,

With Greetings we are informing you that your paper has been successfully published in the International Journal of Emerging Technologies and Innovative Research (ISSN: 2349-5162). Following are the details regarding the published paper.

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Registration ID : JETIR 508727

Paper ID : JETIR2302292

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DOI :

Published in : Volume 10 | Issue 2 | 2023-02-21

Publication Date: 2023-02-21

Page No : c708-c713

Published URL : <http://www.jetir.org/view?paper=JETIR2302292>

Authors : Arman Ahmad

Thank you very much for publishing your article in JETIR. We would appreciate if you continue your support and keep sharing your knowledge by writing for our journal JETIR.

Editor In Chief

International Journal of Emerging Technologies and Innovative Research
(ISSN: 2349-5162)

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